



NEWS FROM.....

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NanoTech-America, Inc. opens new doors into the US SPM market

(Springfield, MA, Dec 1, 2003). Scanning probe microscopy (SPM) is rapidly taking center stage in both materials research, production, and nanotechnology. NanoTech-America, Inc. (NTA), a new national SPM distributor, is positioned to help this vital technology grow.

Unlike most newcomers who start with one or two models, NTA will offer a full line of scanning probe technologies by partnering with the well-known Russian SPM firm, *Nanotechnology and Molecular Device Technology* (NT-MDT). Celebrating its 10-year anniversary this year, NT-MDT is well established in Europe and the Far East (notably, Taiwan) but has had only limited representation in the United States. NTA chose to represent NT-MDT because of their extensive expertise in scanning probe technology as well as the progressive entrepreneurial vision of their president and founder, Dr. Victor Bykov.

The newly-available line of SPMs starts with simple, tabletop models, and includes rugged multi-purpose systems that are ideal for multiple user facilities, as well as high-end magnetic imaging, large format, and high vacuum systems. All are built of titanium with sapphire bearings for long-life and high reliability. Since the entire family of microscopes is designed around a small selection of stands, these modular systems provide excellent, economic growth paths for labs interested in starting simply and moving on to more advanced studies. This new line of microscopes truly allows SPM to become a standard part of the analytical scheme.

In addition to the SPM business, NTA will be opening a web store for cantilevers, highly oriented

pyrolytic graphite, and a wide variety of calibration standards. Currently, the cantilevers are available by emailing cantilevers@nt-america.com.

To get to market quickly, NTA has taken a unique orientation to business: they rely primarily on highly experienced, outsourced talent. Bill Miller of *bill miller sales & consulting* (BMSC) will lead the sales team and has already identified nearly a dozen reps to serve the US market. Bill is well known in the microscopy community from his days at Zeiss, Sarastro and, more recently, as a distributor for Teitz cameras, video-imaging systems from Hi-Scope, and Camscan electron microscopes.

Barbara Foster of Microscopy/Marketing & Education, Inc. will manage the new company's launch and structure their marketing program. The US operation will be supported by a joint US-Russian technical team, headed by a US Technical Applications specialist to be named shortly.

Local logistics will be managed by a small in-house staff.

For further details, visit www.nt-america.com or call Barbara Foster at 413-693-0010.

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Scanning probe microscopy encompasses a family of surface measurement and analysis techniques. The SPM "feels" the surface by means of a special, cantilever-mounted probe. The name of each technique in the family is derived from the probe-surface interaction. For instance, Atomic Force Microscopy (AFM) senses and maps the tiny atomic attractions and repulsions between the tip and the surface while Magnetic Force Microscopy (MFM) senses and maps the magnetic interactions. SPMs can image and quantify the following surface characteristics: adhesion, friction, viscoelasticity (including Young's modulus), magnetic domains, spreading resistance, voltage, capacitance, thermal response (Scanning Kelvin Probe Microscopy), and scanning tunneling energy. Depending on the technique, these measurements can be made in air, liquid, or under external magnetic fields.